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INCEPTION OF SNAPOVER AND GAS INDUCED GLOW DISCHARGES

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Abstract

Ground based experiments of the snapover phenomenon were conducted in the large vertical simulation chamber at the Glenn Research Center (GRC) Plasma Interaction Facility (PIF). Two Penning sources provided both argon and xenon plasmas for the experiments. The sources were used to simulate a variety of ionospheric densities pertaining to a spacecraft in a Low Earth Orbital (LEO) environment¹⁻⁴. Secondary electron emission is believed responsible for dielectric surface charging, and all subsequent snapover phenomena observed^{2, 5}. Voltage sweeps of conductor potentials versus collected current were recorded in order to examine the specific charging history of each sample. The average time constant for sample charging was estimated between 25 and 50 seconds for all samples. It appears that current drops off by approximately a factor

of 3 over the charging time of the sample. All samples charged in the forward and reverse bias directions, demonstrated hysteresis. Current jumps were only observed in the forward or positive swept voltage direction. There is large dispersion in the critical snapover potential when repeating sweeps on any one sample. The current ratio for the 1st snapover region jumps between 2 and 4.6 times, with a standard deviation less than 1.6. Two of the samples showed even larger current ratios. It is believed the 2nd large snapover region is due to sample outgassing. Under certain preset conditions, namely at the higher neutral gas background pressures, a perceptible blue-green glow was observed around the conductor. The glow is believed to be a result of secondary electrons undergoing collisions with an expelled tenuous cloud of gas, that is outgassed from the sample. Spectroscopic measurements of the glow discharge were made in an attempt to identify specific lines contributing to the observed glow.

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I. Introduction

Snapover describes a sudden and rather dramatic change in the current collection regime in and around positively biased conductors that are surrounded by a dielectric⁶⁻⁹. Specifically there is a dramatic transition from the normal current collection regime to a regime exhibiting high current collection. Such current jumps can only be

brought about by successively biasing a conductor to increasing positive bias potentials, in a time interval, that is comparable to the charging time of the dielectric. Dielectric surface charging is brought about by secondary electron emission^{5, 6, 9}. A small percentage of primary electrons, having the proper energy and trajectory, will be focused onto the surface of the dielectric by the E-field. The focusing effects are typically limited to a small area of the dielectric, extending over a small radial distance $\approx 1-2$ cm from the outward edge of the conductor/dielectric interface. As primary electrons strike the dielectric one or more secondaries can be liberated. As the sheath area grows, the surface of the dielectric quickly charges to a positive potential. Secondary electrons, suffering collisions with the outgassed species, are responsible for excitation and the resulting glow. Ferguson et al. reported snapover-induced glow in ground tests using argon, xenon and neon plasmas¹⁰.

The increased complexity of modern spacecraft is fueling the requirement for higher voltage power system designs. Others have previously demonstrated that the high voltage spacecraft systems are capable of undergoing significant physical interactions with the plasma environment^{11, 12}. The 160 V solar array, designed to provide power, for the International Space Station represents a prime example^{9, 11}. A solar array is most vulnerable to snapover at the instant it comes out of eclipse into full sunlight. The solar array voltage will quickly ramp up to full operating potential. With current spacecraft solar array voltages, and the large number of conductor and dielectric surfaces in close proximity, there is increased danger of snapover induced electrical discharges disrupting spacecraft power systems¹³⁻¹⁵.

II. Experimental Test Apparatus

All snapover electrical and optical experiments were run in a 1.8m diameter by 3m high vertical vacuum chamber. Two penning type plasma sources provided plasma for the experiments. The penning sources use a hot filament to ionize either argon or xenon neutral gas which is slowly bleed into the chamber through a controllable leak valve. An ionization gauge was used to measure chamber pressure as gas was added to the chamber via the leak valve. Electron plasma number densities for the experiments ranged from 2×10^5 to 4.0×10^6 electrons/cm³ and electron temperatures were on the order of 1-3.5 eV.

Figure 1: Sample coupon testbed used in snapover experiments.

A sample table was constructed of fiberglass and was mounted in a vertical position in the vacuum chamber. Twenty sample coupons of various types (see figure 1) were then affixed to the sample table so that they could be clearly observed through an optical viewing port on the chamber wall. The sample coupons consisted of a central conductor of a specific metal type (copper or aluminum) and geometry (cylinder or hemispherical), imbedded in a 0.635cm thick by 10.16cm long by 10.16cm wide square of dielectric material. Cylinder

diameters for both copper and aluminum conductors are given on the sample key at the bottom of figure 1. All conductors, with the exception of the hemisphere, were mounted flush with the top surface of the dielectric. Sample coupons were then prepared with a dielectric composed of Kapton, Teflon, or silicon dioxide (SiO₂).

Electrical connections were made to the backside of the conductor and each sample coupon was connected to a separate electrical feed through. The exposed back of each conductor was then insulated with a silicone type adhesive. All sample coupons were electrically floated in the vacuum chamber. A programmable source and measure unit allowed a single conductor sample to be swept with respect to the chamber ground, while simultaneously measuring the current at each bias voltage step. In this way it was possible to obtain a volt/ampere curve for each sample.

Figure 2: Spectrometer setup used in analyzing snapover-induced glow.

For the snapover-induced glow experiments a single 1.27cm aluminum-Teflon coupon test sample was mounted on a separate insulated stand. The coupon was positioned so that it could be clearly seen through a 15.24cm diameter quartz window mounted on the vacuum chamber wall. Insulated electrical connections were then

made between the sample and the electrical feedthrough port.

A 10cm diameter double convex lens with a focal distance of 24cm was mounted inside the chamber, between the sample and quartz optical viewing port. The position between the lens and the sample was adjusted at 85cm, so that the nearly parallel light rays from the sample would be focussed just outside the optical view port. The position of the spectrometer was then adjusted so that the focal point of the lens would fall exactly on the 50 μ wide entrance slit. A black cylindrical light shield tube was constructed around the lens and the optical view port to shield stray light generated by the plasma sources.

This spectrometer employs a Czerny-Turner optical design (see figure 2). Light passing through the entrance slit undergoes 3 specular reflections before passing through the exit assembly. The focal length of the instrument is 156mm. The grating has 1200 grooves per mm, and was cut with a blaze angle centered on 300nm peak intensity. The usable wavelength range for this particular grating is 190nm to 600nm. The manufacturer claims a resolution of 1nm for the instrument.

Light passing from the exit assembly is detected by a charge-coupled device (CCD). The detector/controller is plumbed with 2 lines, a chilled water to cool the detector head and a dry gaseous nitrogen line to prevent against condensation. Information that is gathered by the controller/detector is passed to a computer via a parallel interface and card. Appropriate software, provided by the manufacturer, was used to capture and store information displayed on the computer screen.

III. Experimental Snapover Results

The first series of tests were run to determine the time constant of the sample. The sample was biased from $V=0$ volts potential and then immediately to some large positive potential. Figure's 3.a and 3.b show the current to the sample recorded at various time intervals. These hand plots show the charging constant, τ to be roughly between 25s and 50s. Note that the current drops by a factor of 3 over the time constant in figure's 3.a and 3.4. The floating potential, V_f was measured at 5.5 volts in these tests.

Figure 3a: Sample curve for sample biased from 0 to +600 volts.

Figure 3.b: Sample curve for sample biased from 0 to +700 volts.

The next series of tests involved snapover. The 1.27cm copper-Teflon sample was biased up in an argon plasma. The neutral gas background pressure, $P_0 = 7.3 \times 10^{-5}$ Torr, the plasma number density, $N_e = 2$

$\times 10^5 \text{ cm}^{-3}$ and the electron temperature, $T_e = 3.5 \text{ eV}$. A sweep was made by biasing the conductor from -100V to +400V in 10V steps with a step time 0.5s at each bias voltage. There are several irregularities in the forward biased voltage-current trace (figure 3.a). The observed hook at the first large current jump at 200V is believed to be due to outgassing of the sample. (More will be said about outgassing later.) A sweep in the reverse bias direction (figure 3.b) does not show any peculiarities. Note the hysteresis between the forward and reverse bias traces in figures 4.a and 4.b.

Figure 4a: Forward bias sweep showing current jumps at 200V, 300V & 380V.

Figure 4.b: Reverse bias sweep shows a smooth curve sweep typical of a conductor.

In order to verify the effect of current jumping two more sweeps have been obtained from the same 1.27cm copper-Teflon coupon (sample 19). Figure 5.a

demonstrates the single large current jump at 250V is thought to be a result of outgassing. The "hook" in the curve at 250V is characteristic of a gas discharge at high voltage. Figure 5.b appears to demonstrate a shifting of the critical voltage to a higher snapover potential. If this effect is due to outgassing we should observe the disappearance of the large current jump at 250V in the second sweep of sample 19. Also note the absence of the hook in figure 5.b appears to demonstrate that the sample is well outgassed.

Figure 5.a: Current-voltage sweep at 10:30 a.m., 10V steps and 0.5s per step.

Figure 5.b: Current-voltage sweep at 2:30 p.m., 10V steps and 0.5s per step. The critical voltage shifted to 300V.

The sample coupons have been sitting in the vacuum chamber for some 48 hours. Assuming the effect of current jumping is caused by outgassing one should observe a rise in the critical voltage for

snapover on coupon sample 19. In reality the critical voltage was measured at 200V for the virgin sample. After sitting in vacuum for a few hours the critical voltage increased to about 300V (figure 5.b). The critical voltage then decreases to 275V after sitting in the vacuum chamber for another 20 hours (figure 5.c).

Figure 5.c: Critical voltage decreases from 300V to 275V but the effect is repeatable.

It was decided to keep the sample coupons in the vacuum for a much greater length of time (3 more days) before continuing the tests on the other samples. For the proceeding tests $P_0 = 7.3 \times 10^{-5}$ Torr (consisting of argon gas neutrals), $N_e = 3.3 \times 10^{15} \text{ cm}^{-3}$, and $T_e = 2.2 \text{ eV}$ for the experiments. In order to obtain good statistical results a minimum of 10 sweeps were performed on each sample coupon. The results of these results are summarized in Table 1.

Coupon Type	Sample Size (cm)	Sample #	Snapover Voltage [V]	Standard Deviation	Current Ratio	Standard Deviation	Increase (in Area)	Standard Deviation
Copper-Teflon	1.270	1	279	25	3.18	0.87	2.88	1.27
Copper-Teflon	1.270	2	289	47	4.60	1.23	2.34	0.52
Aluminum-Teflon	1.270	3	243	6	4.50	0.17	3.40	0.70
Copper-Teflon	0.317	4	230	23	47.0	16.0	43.0	13.6
Copper-Teflon	0.525	9	316	51	29.0	21.0	21.7	16.0
Copper-Teflon	2.540	12	198	6	3.25	1.00	2.18	0.53
Copper-Teflon	5.080	16	211	14	1.96	0.33	1.91	0.33
Aluminum-Teflon	0.525	17	268	12.6	4.70	1.60	2.97	0.96
Copper-SiO2 (Glass)	0.525	18	222.5	4.64	4.90	0.87	16.9	1.46

Table 1: Summary of snapover results for various sample coupons.

The snapover results reported in table 1 need further explanation. Three standard measurements are shown in table 1: Snapover Voltage, Current Ratio, and Increase in area. These tabular values represent the mean value for 10 independent measurements of the particular parameter in of interest for a given sample. To the right of each standard measurement is a field containing the standard deviation or spread of values about the mean determination.

The snapover voltage refers to the inception voltage at the 1st current jump (1st snapover region). The current ratio is a scalar factor referring to the magnitude of the collected current. This magnitude is computed by dividing the current maximum by the current minimum in the 1st snapover region. Finally the increase in area is a fictitious term referring to the effective increase in sheath collecting area. The increase in collected area is governed by sheath size; orbit limited current collection, secondary yield, E-field, and surface conductivity. The increase in area is computed from the ratio of the slopes of the current-voltage curve directly before and after the 1st jump in current at the inception voltage.

Statistical data for snapover inception voltage appears to be widely scattered for all samples. It is interesting to note that sample 16, the largest conductor of all samples tested, showed a second large current jump in all ten sweeps. Samples 4 and 8 showed large dispersion in their standard deviations for all three standard measurements. The reason for the large dispersions is believed to be due to contamination of dielectric surfaces. After completing the various snapover tests on the samples and after completing the initial glow observations, it was discovered that

yellow stains were found around all electrodes of the biased samples. An inspection of these stains, performed by three pairs of experienced eyes, have confirmed that the contamination is diffusion pump oil possibly due to a valve failure experienced earlier. None of the unbiased virgin samples inspected showed stains of any kind. The samples were cleaned with a methyl alcohol wash and returned to the vacuum chamber after drying.

IV. Optical Results

In order to verify the hypothesis of a gas discharge at high voltage, our eyes and a color video camcorder has been employed. Previous attempts at GRC to see snapover induced glow with the human eye proved allusive, even at voltages as high as 600V. Such gaseous discharges were strongly felt to result from Paschen breakdown. If vacuum arc ignition is indeed the cause of such gaseous discharges then the glow would be strongly dependent on two parameters: pressure and voltage¹⁶. Since changes in voltage alone failed to produce the glow, it was decided that the other parameter pressure needed to be adjusted.

An argon plasma was established in the vacuum chamber with a much greater neutral gas background pressure ($P_0 = 3 \times 10^{-4}$ Torr) then previously used. Next a previously unbiased virgin sample (sample 11) was slowly swept from +100V to +600V in 5V steps. The voltage was applied over a time of 500ms at each step. As the sample was swept, observations of the sample were made with the unaided eye through the vacuum chamber's optical view port. An 8cm diameter blue-green glowing ring of gas was detected around the electrode at approximately 515V. The glow lasted about 10s before extinguishing. A second attempt

at biasing sample 11 failed to produce the glow. The absence of the glow appears to confirm the initial suspicion of sample outgassing. It is suggested here that sample outgassing, due to gas and/or water vapor trapped between the conductor-dielectric interface, is responsible. In fact a blue color is often seen in plasmas where water vapor is present.

Moving to a new virgin sample (sample 2) a camcorder was set up to record the glow. The sample was biased positive and the glow (see figure 6) was recorded. Figure 7 shows the voltage-current sweep for the glow recorded shown in figure 6.

Figure 6: Example of snapover induced glow discharge.

Figure 7: Gaseous discharge begins at about 430V potential.

The final series experiments were performed in an attempt to obtain a glow discharge spectrum. Sample 19 was cleaned and mounted in the tank facing the quartz optical view port. An argon lamp was mounted in front of the sample. The distance of the culminating lens was adjusted to a sharp focus on the slit. For calibration purposes, an argon spectrum was obtained by rotating the grating and obtaining a calibration spectrum for argon at the following central wavelengths, (λ): $\lambda = 385\text{nm}$, $\lambda = 400\text{nm}$, $\lambda = 420\text{nm}$, $\lambda = 435\text{nm}$, $\lambda = 450\text{nm}$ and $\lambda = 470\text{nm}$. A sample argon spectrum with the spectrometer adjusted on the 420nm line is shown in figure 8. The overall estimate of error for this conversion process is 1nm (10 angstroms) ¹⁷.

Figure 8: Sample argon calibration spectrum with two of the most intense lines labeled.

In reality the output obtained from the instrument software is given in terms of pixels (scalar) and intensity (relative units). Conversion from pixels to wavelength, λ , is obtained from the following equation:

$$\lambda(p) \cong 420.1 - k(p - b(\lambda_c))$$

Where p = pixel number, $k = 0.125$ nm per pixel, $\lambda_c = 385\text{nm}$, 400nm , 420nm , 435nm , 450nm and 470nm (central wavelength)

adjustment set on the spectrometer), $b(385) = 246.5$, $b(400) = 370.5$, $b(420) = 534.5$, $b(435) = 654.5$ and $b(450) = 774.5$. Exact details of the conversion process as well as estimate of errors can be found in Vayner et. al. (reference 17).

Having completed the calibration of the spectrometer the argon lamp was removed and the vacuum chamber was pumped down. The tank pressure with the argon plasma sources operating was $P_o = 3.2 \times 10^{-4}$ Torr.

In practice the spectrometer is adjusted to a specific central wavelength, λ_c and a background trace was acquired. The plasma source hot filaments produce a modest wide band background signal centered at about 550nm. This background needs to be subtracted from every glow spectrum acquired. The background also needs to be newly acquired ever time the spectrometer central wavelength is re-adjusted. A minimum of two glow spectra was acquired at each λ_c specified in the argon calibration spectrum. Figure 9 shows a typical glow spectrum obtained in an argon plasma.

Figure 9: Glow spectrum in argon plasma. Spectrometer set for $\lambda_c = 420$ nm.

It should be noted that a shift to higher frequencies in λ_c translates to a shift

to the right (shift to higher λ 's) in the acquired spectrum.

The final series of measurements were aimed at obtaining a glow discharge spectrum in the presence of a xenon plasma. The base operating pressure with the plasma sources on was $P_o = 2 \times 10^{-4}$ Torr. Once again, a minimum of two glow discharge spectra was acquired at each λ_c specified in the argon calibration spectrum. Background traces obtained at each shift in λ_c were subtracted from the corresponding glow discharge spectrum. Figure 10 demonstrates a typical glow spectrum obtained in a xenon plasma.

Figure 10: Glow spectrum in a xenon plasma. Spectrometer set $\lambda_c = 385$ nm.

A direct comparison of spectrum measurements performed for different λ_c in both argon and xenon plasmas are made. These comparisons were used to determine the most reliable lines and common lines in the glow discharge spectrum.

For argon plasmas the following lines were identified: 403, 410, 414, 418, 420.6, 425, 428.6, 438, 444, 456 and 461/63. In xenon plasmas the following lines were also identified: 371, 398/401, 412/415, 419, 422/24 and 454. The MIT Tables¹⁸ show the most intensive lines for xenon occur at 419nm, 414nm and 398nm. Lines at 414nm in argon and the 412/415 lines for xenon

may belong to some other species in the glow spectrum. No lines for xenon were found at 401nm. Lines for oxygen at 412nm, for copper at 412nm and for OII at 414nm were found. There is a strong line for xenon at 454nm. No suitable species was found at 456nm. There are however lines at 457.7nm for OI and a line at 457.9nm for ArII.

V. Conclusion

Snapover and related solar array interactions with the space plasma environment are issues of great importance. An understanding of the snapover phenomenon is therefore valuable to solar array system design and survivability. Modern high power solar arrays are currently being used in a number of spacecraft. A number of these spacecraft are experiencing problems that can be related to snapover. Large planar arrays, incorporating insulators adjacent to exposed conductors in the space plasma, can effectively collect current as if they were conductors. Such enhanced plasma current collection was detected in the laboratory on the PASP Plus flight arrays⁴. The reason for this type of current collection behavior is due to enhanced surface conductivity resulting from secondary electron emission. The present experiments were conducted to study the effects of enhanced current collection in the laboratory for a number of different dielectrics and conductor types.

Snapover induced glow discharges, a related phenomenon, was also studied at pressure ranges between 10^{-4} and 10^{-5} Torr. Although these pressures are much higher than what might ordinarily be found in low Earth orbit, they are more typical of what might be found during brief periods of spacecraft thruster firings. Spectroscopic analysis of the glow discharge has allowed several lines contributing to the glow to be

isolated, but not the contributing species. It is hoped the present study is beneficial to the scientific community.

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